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Paper No. 36

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OFFICE OF PETITIONS

In re Application of DeBonte et al.

Application No. 08/572,027

DECISION ON PETITION

Filed: 14 December, 1995

Attorney's Docket No. A21-535.1007:

This is a decision on the renewed petition filed by facsimile on 18 March, 2002 (certificate of mailing date 21 December, 2001), under 37 CFR 1.47(a), 1.48, and 1.183.

The petition is again dismissed.

Petitioners are given TWO MONTHS from the mailing date of this decision to reply, correcting the below-noted deficiencies. Any reply should be entitled "Request for Reconsideration of Petition Under 37 CFR 1.47(a), 1.48 and 1.183," and should only address the deficiencies noted below, except that the reply may include an oath or declaration executed by the non-signing inventor. FAILURE TO RESPOND WILL RESULT IN ABANDONMENT OF THE APPLICATION. Extensions of time may be obtained in accordance with 37 CFR 1.136(a).

Although the person sought to be added as an inventor, Hua Miao, has now signed the statement of lack of deceptive intent, the declaration submitted with the present petition is defective in that non-initialed and/or non-dated alterations with regard to joint inventors Mias and Debonte. A new declaration in compliance with 37 CFR 1.63 and 1.67 is required.

MPEP 602.01; <u>See</u> 37 GFP 1.1.75 .

Further correspondence with respect to this matter should be addressed as follows:

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Supervisory Petitions Examiner

Office of Petitions

Office of the Deputy Commissioner for Patent Examination Policy